# MSKSEMI 美森科













ESD.

TVS

TSS

MOV

GDT

PIFD

# **BSS138AKDW**

**Product specification** 





#### **General Features**

- 55V,0.3A, RDS(ON) =1.2Ω@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available
- G-S ESD Protection Diode Embedded
- ESD protected up to 2KV

# **Application**

- Motor Drive
- Power Tools
- LED Lighting

### **Reference News**

PACKAGE OUTLINE	Pin Configuration	Marking
SOT-363	D1 D2 G1 G2 G1 S2	***8EX 83K <sub>***</sub>



# Absolute Maximum Ratings (TA=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	55	V
Vgs	Gate-Source Voltage	±20	V
l-	Drain Current – Continuous (T <sub>A</sub> =250)	0.3	Α
lD	Drain Current – Continuous (T <sub>A</sub> =70C)	0.2	А
Ірм	Drain Current – Pulsed <sup>1</sup>	0.9	Α
D-	Power Dissipation (T <sub>A</sub> =250)	0.28	W
PD	Power Dissipation – Derate above 250	0.002	W/ C
Тѕтс	Storage Temperature Range	-50 to 150	С
TJ	Operating Junction Temperature Range	-50 to 150	С

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Rеja	Thermal Resistance Junction to ambient		450	C/ W

# Electrical Characteristics (TJ=25 $^{\circ}$ C , unless otherwise noted)

#### **Off** Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=250uA	55			٧
△BVDSS/△TJ	BV <sub>DSS</sub> Temperature Coefficient	Reference to 250 , ID=1mA		0.04		V/ C
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =55V , V <sub>GS</sub> =0V , T <sub>J</sub> =250			1	uA
Igss	Gate-Source Leakage Current	V <sub>GS=</sub> ±20V , V <sub>DS</sub> =0V			±10	uA



#### On Characteristics

RDS(ON)	Static Drain-Source On-Resistance	VGS=10V , ID=0.3A		1.2	1.5	Ω
(CIV)		VGS=4.5V , ID=0.2A		1.3	2.2	Ω
VGS(th)	Gate Threshold Voltage	VGS=VDS . ID =250uA	0.8	1.1	1.6	V
△VGS(th)	VGS(th) Temperature Coefficient	VGG-VDG , ID -2000A		-4		mV/ C
gfs	Forward Transconductance	VDS=10V , ID=0.1A		0.24		S

Dynamic and switching Characteristics

Dynamic	and switching Charac	161121162		
Qg	Total Gate Charge <sup>2,3</sup>		 1.1	
Qgs	Gate-Source Charge <sup>2,3</sup>	V <sub>DS</sub> =55V , V <sub>GS</sub> =10V , I <sub>D</sub> =0.2A	 0.1	 nC
Qgd	Gate-Drain Charge <sup>2, 3</sup>		 0.23	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>		 3	
Tr	Rise Time <sup>2, 3</sup>	$V_{DD}$ =55 $V$ , $V_{GS}$ =10 $V$ , $R_{G}$ =6 $\Omega$	 5	 ns
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	Ip=0.2A	 14	
Tf	Fall Time <sup>2, 3</sup>		 9	
Ciss	Input Capacitance		 30.6	
Coss	Output Capacitance	V <sub>DS</sub> =10V , V <sub>GS</sub> =0V , F=1MHz	 5.5	 pF
Crss	Reverse Transfer Capacitance		 4	

### Drain- Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			0.3	Α
lsм	Pulsed Source Current				0.6	Α
VsD	Diode Forward Voltage	Vgs=0V , Is=1A , TJ=250			1.4	V

#### Note:

- 1 . Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq$  300 us , duty cycle  $\leq$  2% .
- 3. Essentially independent of operating temperature.



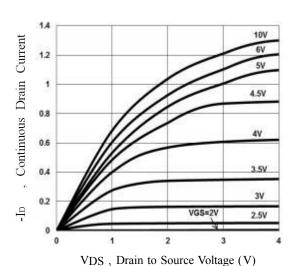


Fig. 1 Output Characteristics

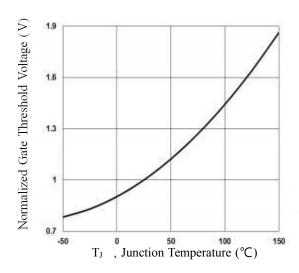


Fig. 3 Normalized RDSON vs. TJ

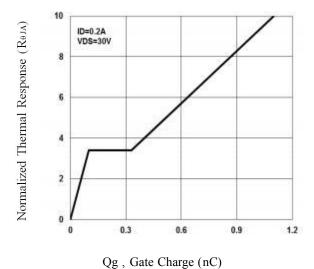
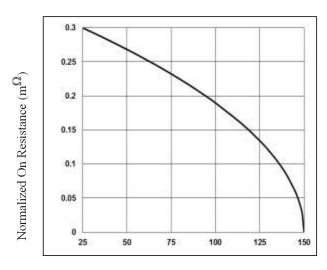
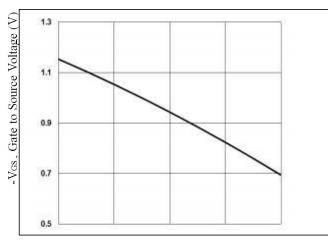


Fig. 5 Gate Charge Waveform



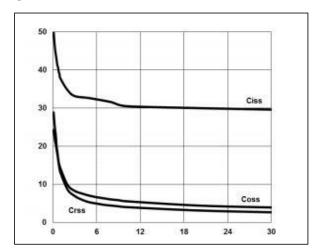
TJ, Juction Temperature(°C)

Fig. 2 Continuous Drain Current vs. TJ



TJ, Juction Temperature(°C)

Fig. 4 Normalized Vth vs. TJ



-VDS, Drain to Source Voltage (V)

Fig. 6 Capacitance Characteristics

-ID, Continuous Drain Current (A)



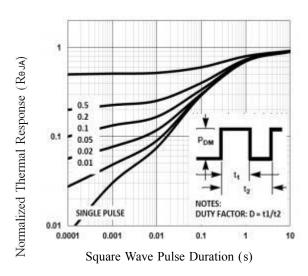


Fig. 7 Normalized Transient Impedance

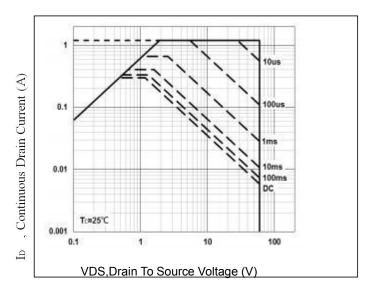


Fig. 8 Maximum Safe Operation Area

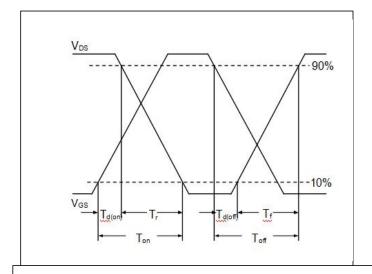
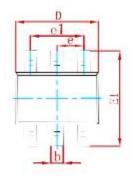


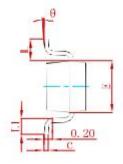
Fig. 9 Switching Time Waveform

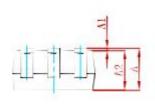




### PACKAGE MECHANICAL DATA

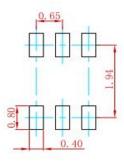






Symbol	Dimensions	In Millimeters	Dimensions	In Inches
Syllibol	Min	Max	Min	Max
Α	0.900	1.100	0.035	0.043
A1	0.000	0.100	0.000	0.004
A2	0.900	1.000	0.035	0.039
b	0.200	0.400	0.008	0.016
С	0.080	0.150	0.003	0.006
D	2.000	2.200	0.079	0.087
E	1.150	1.350	0.045	0.053
E1	2.150	2.450	0.085	0.096
е	0.650	0.650 TYP		S TYP
e1	1.200	1.400	0.047	0.055
L	0.525	REF	0.021 REF	
L1	0.260	0.460	0.010	0.018
9	0°	8°	0°	8°

# **Suggested Pad Layout**



- Note:
  1.Controlling dimension:In millimeters.
  2.General tolerance:±0.05mm.
  3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
BSS138AKDW	SOT-363	3000



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